



Applicant(s)/Patent Under Reexamination CHAN ET AL.

Art Unit

2815

Examiner Chris C. Chu

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## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-20020074669 - A1	06-2002	Watanabe et al.	257/777
<u> </u>	В	US-20020017721 - A1	02-2002	Huang	257/724
	С	US-6376907 - B1	04-2002	Takano et al.	257/704
	D	US-6208525 - B1	03-2001	Imasu et al.	361/783
	Ε	US-6157080 - A	12-2000	Tamaki et al.	257/738
	F	US-5872051 - A	02-1999	Fallon et al.	438/616
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## FOREIGN PATENT DOCUMENTS

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## **NON-PATENT DOCUMENTS**

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*	<u> </u>	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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